

## Supplementary Materials

# Epitaxial Growth and Structural Characterizations of MnBi<sub>2</sub>Te<sub>4</sub> Thin Films in Nanoscale

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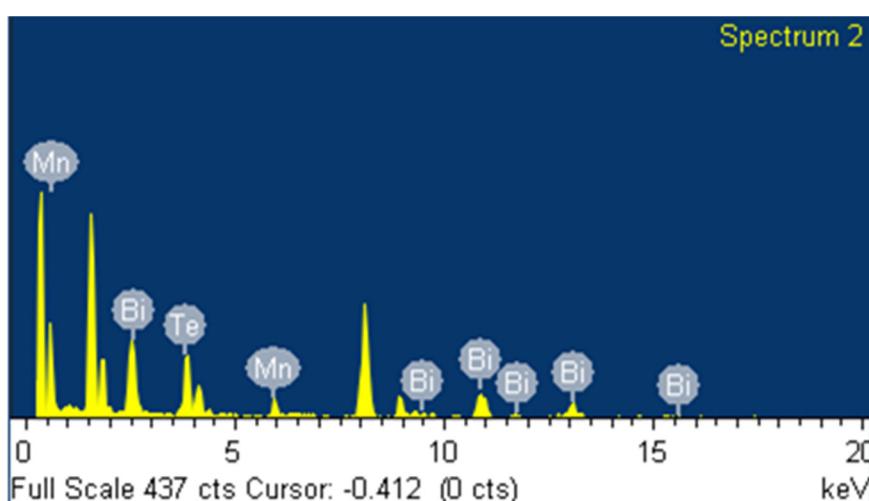
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**Supplementary Note 1. TEM-EDX spectrum of MnBi<sub>2</sub>Te<sub>4</sub> film.**



**Figure S1.** TEM-EDX spectrum recorded on the MnBi<sub>2</sub>Te<sub>4</sub> film.

Typical TEM-EDX analysis of the atomic ratios of Bi, Mn and Te of the sample; the results are summarized in Table S1.

Table S1. Atomic ratio of Bi, Mn and Te of the sample.

Element	Mn	Bi	Te
Atomic (at %)	13.97	30.29	55.74